

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/010,947	HAINES ET AL.	
Examiner	Art Unit	
Raquel Alvarez	3622	

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EIC SEARCH	1/8/2008	R.A.		